TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT SILICON MONOLITHIC

T 6 L 2 4

SOURCE DRIVER FOR TFT LCD PANELS

The T6L24 is a 240-channel-output source driver for TFT LCD panels.

The T6L24 offers both low power consumption and high integration circuit due to CMOS technology.

FEATURES

• LCD drive output pins : 240 pins (80 pins each for R, G

and B)

Power supply voltage : Digital power supply voltage

··· 2.7 to 5.5 V

Analog power supply voltage

··· Max 5.5 V

Sampling method : 2 latches

Data transfer method : Bi-directional shift register

Operating temperature : -20 to 75°C

: Tape carrier package (TCP) Package

Switching simultaneous/sequential sampling

Unit: mm USER AREA PITCH T6L24 OUT (SDN, 5ES) 0.85 0.09

Please contact Toshiba or an authorized Toshiba dealer for information on package dimensions.

TCP (Tape Carrier Package)

Polyimide base film is hard and thin. Be careful not to injure yourself on the film or to scratch any other parts with the film. Try to design and manufacture products so that there is no chance of users touching the film after assembly, or if they do, that there is no chance of them injuring themselves. When cutting out the film, try to ensure that the film shavings do not cause accidents. After use, treat the leftover film and reel spacers as industrial waste.

Light striking a semiconductor device generates electromotive force due to photoelectric effects. In some cases this can

cause the device to malfunction.

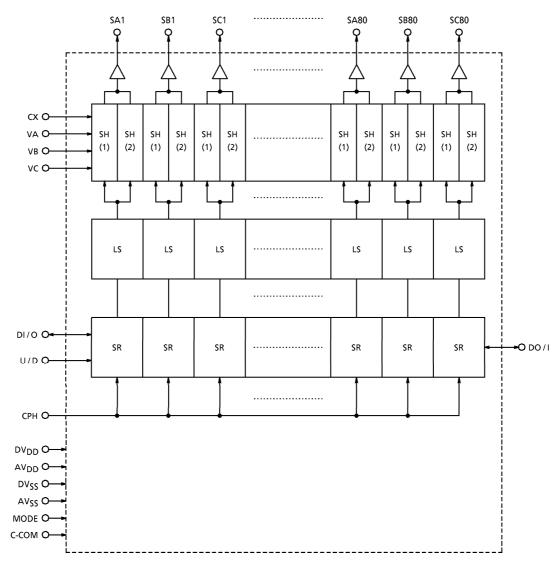
This is especially true for devices in which the surface (back), or side of the chip is exposed. When designing circuits, make sure that devices are protected against incident light from external sources. Exposure to light both during regular operation and during inspection must be taken into account.

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BLOCK DIAGRAM

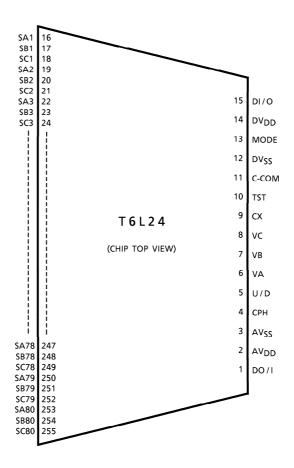


SR : Shift Register

LS : Level Shifter

SH: Sample-and-Hold Circuit

PIN ASSIGNMENT



The above diagram shows the device's pin configuration only and does not necessarily correspond to the pad layout on the chip. Please contact Toshiba or our distributor for the latest TCP specification.

TOSHIBA

PIN FUNCTION

PIN NAME	1/0	FUNCTION						
		Vertical shift data I/O pins These pins are used to input and output shift data. These pins are switched between input and output by setting the U/D pin as shown below:						
		U/D DI/O DO/I						
		H Input Output L Output Input						
DI/O DO/I	1/0	 When set for input When MODE = low						
U/D	I	Transfer direction select pin This pin specifies the direction of sampling performed by the sample-and-hold circuit. • When MODE = low When U/D is high, data is sampled in the sequence SA1→SB1→SC1→SA2→SB2→····→SC80 When U/D is low, the sequence is reversed to give SC80→SB80→SA80→SC79→····→SA1 • When MODE = high When U/D is high, data is sampled in the sequence SA1, SB1, SC1→SA2, SB2, SC2→····→SA80, SB80, SC80 When U/D is low, the sequence is reversed to give SC80, SB80, SA80→SC79, SB79, SA79→····→SC1, SB1, SA1						
СРН	I	Shift clock input This clock sequentially shift the signals necessary to sample the data that are output to the LCD drive output pins (QA1 to QC80).						
СХ	I	Sample-and-hold switching pin. This pin switches between two sample-and-hold circuits.						
MODE	I	Sampling mode setting pin. When MODE = high Simultaneously samples three video output signals corresponding to the LCD drive outputs. When MODE = low Sequentially samples the video output signals corresponding to the LCD drive outputs.						

T6L24

PIN NAME	1/0	FUNCTION				
VA		Analog signal input				
VB	- 1	These pins accept as their input the analog signals that are output to the				
VC		LCD drive output pins.				
		Sample and hold reference voltage input				
C-COM	I	This is the reference voltage for the sample-and-hold circuit.				
		Apply stable DC voltage to the pin.				
QA1 to QA80		LCD drive output pins				
QB1 to QB80	0	These pins output one of the analog signal inputs (VA, VB and VC) after it				
QC1 to QC80		has been sampled and held by the sample-and-hold circuit.				
DV _{DD}		Power supply for the device's logic block				
AV _{DD}		Power supply for the device's high-voltage block				
DVSS		Digital GND for the device				
AVSS		Analog GND for the device				
TST		Test pin				
131		Use the pin as required.				

DIVICE OPERATION

(1) Analog signal sampling

Data transfer begins with the assertion of DI/O (U/D = high) or DO/I (U/D = low).

<Simultaneous sampling>

● When MODE = high, U/D = high

A high on DI/O is latched into the internal logic synchronously with the rising edge of CPH, and the analog signal to be output to (SA1, SB1, SC1) is sampled at next rising edge of CPH. In this way, all analog signals are sampled of each three channel sequentially at the rising edge of CPH and so on, and the analog signals are output to (SA2, SB2, SC2), (SA3, SB3, SC3) and so on. After the device finishes sampling the data for (SA80, SB80, SC80), it automatically enters standby state. Unless DI/O is asserted again, no data is sampled, irrespective of whether CPH are input to the device.

When MODE = high, U/D = low

A high on DO/I is latched into the internal logic synchronously with the rising edge of CPH, and the analog signal to be output to (SA80, SB80, SC80) is sampled at next rising edge of CPH. In this way, all analog signals are sampled of each three channel sequentially at the rising edge of CPH and so on, and the analog signals are output to (SA79, SB79, SC79), (SA78, SB78, SC78) and so on.

After the device finishes sampling the data for (SA1, SB1, SC1), it automatically enters standby state. Unless DO/I is asserted again, no data is sampled, irrespective of whether CPH are input to the device.

<Sequential sampling>

When MODE = low, U/D = high

A high on DI/O is latched into the internal logic synchronously with the rising edge of CPH, and the analog signal to be output to SA1 is sampled at the rising edge of CPH after three clock period. In this way, all analog signals are sampled sequentially at the rising edge of CPH and so on, and the analog signals are output to SB1, SC1, SA2, SB2, SC2, SA3, SB3, SC3 and so on.

After the device finishes sampling the data for SC80, it automatically enters standby state. Unless DI/O is asserted again, no data is sampled, irrespective of whether CPH are input to the device.

When MODE = low, U/D = low

A high on DO/I is latched into the internal logic synchronously with the rising edge of CPH, and the analog signal to be output to SC80 is sampled at the rising edge of CPH after three clock period. In this way, all analog signals are sampled sequentially at the rising edge of CPH and so on, and the analog signals are output to SB80, SA80, SC79, SB79, SA79, SC78, SB78, SA78 and so on

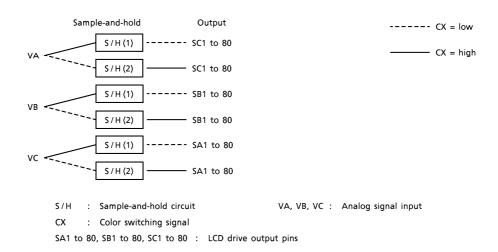
After the device finishes sampling the data for SA1, it automatically enters standby state. Unless DO/I is asserted again, no data is sampled, irrespective of whether CPH are input to the device.

(2) LCD drive output

• The T6L24 has two sample-and-hold circuits called Sample-And-Hold (1) and (2). These two circuits alternate between serving as the output and the sample-and-hold. Which circuit fulfils which function is determined by the setting of the CX pin.

сх	ОИТРИТ	SANPLE-AND-HOLD
L	Sample-and-hold circuit (1)	Sample-and-hold circuit (2)
Н	Sample-and-hold circuit (2)	Sample-and-hold circuit (1)

- The analog signal inputs VA, VB and VC are output as follows: VA is sent to the LCD driver output pins SC1 to SC80, VB is sent to output pins SB1 to SB80, and VC is sent to output pins SA1 to SA80. The analog signal inputs will be sent to LCD driver output pins by the setting of the CX pin as shown below:
 - (*) The CX pin setting must not be altered while the device is sampling data.



(3) Vertical shift data output

When MODE = high

The output DO/I (U/D = high) or DI/O (U/D = low) is driven high for one clock period synchronously with the rising CPH, one clock period before the data (which is to be output to (SA80, SB80, SC80) or (SA1, SB1, SC1)) is latched into the shift register.

When MODE = low

The output DO/I (U/D = high) or DI/O (U/D = low) is driven high for one clock period synchronously with the rising CPH, one clock period before the data (which is to be output to SA80 or SC1) is latched into the shift register.

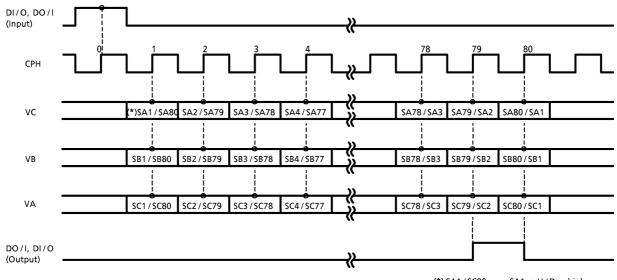
When using two or more of these devices to drive a large screen, connect the vertical shift data output from the first stage of the LCD driver directly to the vertical shift data input at the next stage. In this way, the device's LCD drive output pin can easily be expanded as necessary.

(4) Sample-and-hold reference voltage (C-COM)

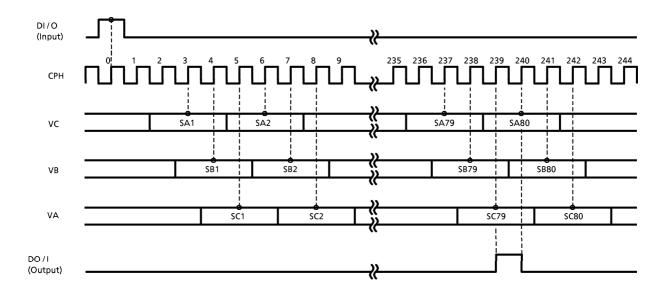
The device's sample-and-hold circuits are configured using the internal capacitors. The C-COM pin is used to supply the reference voltage for these circuits. Apply stable DC voltage to the pin.

TIMING DIAGRAM

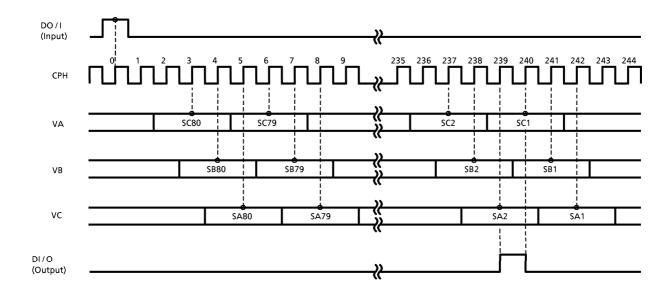
• Simultaneous sampling (MODE = high)



(*) SA1/SC80 : $SA1 \rightarrow U/D = high$ $SA80 \rightarrow U/D = low$ Sequential sampling (MODE = low, U/D = high)



• Sequential sampling (MODE = low, U/D = low)



ABSOLUTE MAXIMUM RATINGS (AV_{SS} = DV_{SS} = 0 V)

	_					
PARAMETER	SYMBOL	RATING	UNIT	RELEVANT PIN		
Supply Voltage (1)	DV _{DD}	-0.3 to 6.5	V			
Supply Voltage (2)	AV _{DD}	-0.3 to 6.5	V			
Digital Input Voltage	V _{IN}	-0.3 to DV _{DD} + 0.3	V	(Note 1)		
Reference Analog Voltage	V _{ID}	-0.3 to AV _{DD} + 0.3	V	(Note 2)		
Storage Temperature	T _{stg}	- 55 to 125	°C			

RECOMMENDED OPERATING CONDITIONS (AV_{SS} = DV_{SS} = 0 V)

PARA	METER	SYMBOL	OL RATING		RELEVANT PIN
Supply Voltage	e (1)	DV_DD	2.7 to 5.5 V		
Supply Voltage	(2)	AV_{DD}	DV _{DD} to 5.5	V	
Reference Ana	log Voltage	V _{ID}	0.2 to AV _{DD} - 0.2	V	(Note 2)
Operating Temperature		T _{OP}	-20 to 75	°C	
Operating	MODE = high	^f CLK	0.5 to 15	MHz	
Frequency MODE = low		^f CLK	0.5 to 30	MHz	
Output Load Capacitance		C_L	50 (max)	pF/PIN	
Input Capacita	nce	C _{IN}	10 (max)	pF	

ELECTRICAL CHARACTERISTICS

DC CHARACTERISTICS (Referenced to DV_{DD} = 3.0 \pm 0.3 V, AV_{DD} = 5.0 \pm 0.5 V, AVSS = DVSS = 0 V, Ta = -20 to 75°C unless otherwise noted

		\ 14 -		75 C dilicis Otherw					
PARAMETER		SYMBOL	TEST CIR- CUIT	TEST CONDITIONS	MIN	TYP.		UNIT	RELEVANT PIN
Input	Low Level	V _{IL}			0		$0.2 \times DV_{DD}$	v	(Note 1)
Voltage	High Level	VIH	_		$0.8 \times DV_{DD}$		DV _{DD}] '	(Note 1)
Output	Low Level	VOL		I_{OL} = 40 μ A	0		0.3	v	DI/O,
Voltage	High Level	VOH	_	$I_{OL} = -40 \mu A$	V _{DD} – 0.3 V		DV _{DD}	\ \	DO/I
Output Offset Voltage		VOFF			- 20		20	mV	SA1 to SC80
Input Current		I _{IN}	_		– 1		1	μ A	(Note 1)
Current Consumption (1)		DI _{DD}					3	mA	DV _{DD}
Current Consumption (2)		AlDD					9	mA	AV _{DD}

(Note 1) : All input pins except the analog signal input pins (VA, VB, VC)

(Note 2) : Analog signal input pins (VA, VB, VC)

AC CHARACTERISTICS (Referenced to DV_{DD} = 3.0 \pm 0.3 V, AV_{DD} = 5.0 \pm 0.5 V, AV_{SS} = DV_{SS} = 0 V, Ta = -20 to 75°C unless otherwise noted

PARAMETER	SYMBOL	TEST CIR- CUIT	TEST CONDITIONS	MIN	TYP.	MAX	UNIT
Operating Frequency	fCPH		MODE = low	0.5		30	MHz
Operating Frequency	(1/tCPH)	_	MODE = high	0.5		15	IVITZ
CPH Pulse Width H	^t CWH	_		12			ns
CPH Pulse Width L	^t CWL	_		12			ns
Data Set-up Time	tDSU	_		5			ns
Data Hold Time	tDHD	_		5			ns
CX Set-up Time	tpdC			5			CPH period
Output Delay Time 1	tpdDO	_	C _L = 30 pF			16	ns
Output Delay Time 2	tpdDS	_	C _L = 50 pF Target output voltage (90%, 10%)			8	μs
Output Delay Time 3	tpdDX		C _L = 50 pF, Target output voltage			15	μs

